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PATENT NUMBER and
ISSUE DATE

U.S. UTILITY Patent Application

APPLICATION NO. 10/000160	CONT/PRIOR F	CLASS 365 714	SUBCLASS 718	ART UNIT 2818 2133	EXAMINER J. J. J. J.
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APPL NUM 10000160	FILING DATE 12/04/2001	CLASS 365	SUBCLASS	GAU 2818	EXAMINER
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****APPLICANTS:** Yamada Takashi;

****CONTINUING DATA VERIFIED:**

**** FOREIGN APPLICATIONS VERIFIED:**
JAPAN 2001-149214 05/13/2001

PTO-2040
12/99

PG-PUB	DO NOT PUBLISH <input type="checkbox"/>	RESCIND <input type="checkbox"/>
Foreign priority claimed <input type="checkbox"/> yes <input type="checkbox"/> no 35 USC 119 conditions met <input type="checkbox"/> yes <input type="checkbox"/> no Verified and Acknowledged Examiners's initials		ATTORNEY DOCKET NO 50090-459
TITLE : Method of testing semiconductor storage device		

U.S. DEPT. OF COMM./PAT. & TM.-PTO-436L (Rev. 12-94)

NOTICE OF ALLOWANCE MAILED		CLAIMS ALLOWED	
ISSUE FEE Amount Due Date Paid		Total Claims Print Claim for O.G.	
		DRAWING Sheets Drwg. Figs. Drwg. Print Fig.	
<input type="checkbox"/> TERMINAL DISCLAIMER		Primary Examiner	
		Application Examiner	
PREPARED FOR ISSUE		WARNING: The information disclosed herein may be restricted. Unauthorized disclosure may be prohibited by the United States Code Title 35, Sections 122, 181 and 368, Possession outside the U.S. Patent & Trademark Office is restricted to authorized employees and contractors only.	

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